







## Cavity History Summary CKM - SCRF 3.9GHz Transverse Mode Cavity

Cavity Description				Cleaning Treatment Summary					RFMeasurement Summary									
CAVITY	BEAM TUBE ID (mm)	PULL- OUTS	WELDING COMPLETED	Rs @Qo = 2.1e9 (nΩ)	CHEMICAL TREATMENT	ETCH DETAILS	HIGH PRESSURE RINSE @JLAB	HIGH PRESSURE RINSE @A0	HEAT TREATMENT DETAILS	RF Test Date	Resonant Frequency (MHz)	Rs (nΩ)	E <sub>D Max</sub> (MV/m)	X-Rays	T @Freq (K)	T @Rs (K)	T @E <sub>D Max</sub> (K)	Rs correc (nΩ)
A15-5C-1o	30	NO		112	??	??	??	??	??	1/31/2001	N/A	330	N/A	N/A	N/A	1.53	N/A	
7110 00 10	,		•		JLAB prior to 5/22/2001	??	??	??	??	5/22/2001	3908.953	??	??	??	??	??	??	
C15-1C-1A	30	NO	11/17/2000	121	JLAB prior to	402	Yes ?Time?	?	?	3/14/2001	3946.3	120	??	Yes	?	1.8	N/A	
	30	NO	11/17/2000	121	2/8/2001	102 μm	res / lille /		,			-						
								< 4/26/2001		4/26/2001 5/1/2001	3964.531 N/A	118 5500	9.7 N/A	Yes ??	1.8 N/A	1.8 2.0	1.8 N/A	
					JLAB - 7/29/01	137 μm	20 min	??		8/31/2001	N/A	1420	N/A	??	N/A	1.89	N/A	
										9/4/2001	3959.690	990	6.3	Yes	1.79	1.8	1.79	
					JLAB - 10/12/01	4 x 1 minute BCP @ 6.2 μm/min Tot.= 25 μm	15 min	10/19/2001	JLAB - 800 C - 6 hrs	11/1/2001	3954.240	180	5.9	No	1.73	1.77	1.79	
		_																
C15-1C-2A	30	YES	3/23/2001	121						8/24/2001	3955.690 3954.000	22350 8500	N/A	N/A ??	1.83 1.75	1.83	N/A	
										9/18/2001	3954.000	6500	1.4	"			1.76	
					II AD 40/40/04	4 x 1 minute BCP @ 6.2	45 .		II A D 000 0 0 1	444510004	0050 000	000	~ ~					
					JLAB - 10/12/01	4 x 1 minute BCP @ 6.2 μm/min Tot.= 25 μm	15 min		JLAB - 800 C - 6 hrs	11/15/2001	3950.980 3950.930	206 190	6.0 5.9	No No	1.71	1.71	1.79	
C15-13C-1A	36	YES	8/27/2001	109	JLAB - 10/12/01		15 min		JLAB - 800 C - 6 hrs								1.79	
C15-13C-1A C15-1C-3A	36	YES	8/27/2001	109	JLAB - 10/12/01	μ <i>m</i> /min Tot.= 25 μm  4 x 1 minute BCP @ 5.4	15 min		JLAB - 800 C - 6 hrs	11/16/2001	3950.930	190	5.9	No	1.70	1.70	1.79	
						μ <i>m</i> /min Tot.= 25 μm		10/21/2002 20up/20dwn	JLAB - 600 C - 10 hrs A0 - 150C Wrap Bake	6/27/2002	3950.930	190	5.9	No	1.70	1.70	1.79	73
						μ <i>m</i> /min Tot.= 25 μm  4 x 1 minute BCP @ 5.4			JLAB - 600 C - 10 hrs	6/27/2002	3950.930 3930.016	190	2.6	No No	1.70	1.70	1.79	73
C15-1C-3A						μ <i>m</i> /min Tot.= 25 μm  4 x 1 minute BCP @ 5.4			JLAB - 600 C - 10 hrs A0 - 150C Wrap Bake	6/27/2002	3950.930 3930.016	190	2.6	No No	1.70	1.70	1.79	
C15-1C-3A	36	NO	10/17/2001	121	JLAB - 02/06/02	μm/min Tot.= 25 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm  4 x 1 minute BCP @ 5.4	15 min	20up/20dwn	JLAB - 600 C - 10 hrs A0 - 150C Wrap Bake 10/30/2002 - 11/3/2002	11/16/2001 6/27/2002 11/7/2002 2/23/2002 3/15/2002	3950.930 3930.016 3976.415 3930.583 N/A	190 1390 1042 234 N/A	5.9 2.6 5.4 5.1 N/A	No No No No No N/A	1.78 1.78 1.78	1.70 1.89 1.79	1.79 1.91 1.80 1.79 N/A	73 137 /
C15-1C-3A	36	NO	10/17/2001	121	JLAB - 02/06/02	μm/min Tot.= 25 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm	15 min	20up/20dwn	JLAB - 600 C - 10 hrs A0 - 150C Wrap Bake 10/30/2002 - 11/3/2002	11/16/2001 6/27/2002 11/7/2002 2/23/2002 3/15/2002 5/1/2002	3950.930 3930.016 3976.415 3930.583 N/A 3930.186	190 1390 1042 234 N/A 265	5.9 2.6 5.4 5.1 N/A 4.8	No No No No No No No No N/A No	1.78 1.78 1.78 N/A 1.78	1.70 1.89 1.79 1.81 N/A 1.79	1.79 1.80 1.79 N/A 1.78	137
C15-1C-3A	36	NO	10/17/2001	121	JLAB - 02/06/02	μm/min Tot.= 25 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm  4 x 1 minute BCP @ 5.4	15 min	2/17/2001	JLAB - 600 C - 10 hrs A0 - 150C Wrap Bake 10/30/2002 - 11/3/2002	11/16/2001 6/27/2002 11/7/2002 2/23/2002 3/15/2002 7/15/2002	3950.930 3930.016 3976.415 3930.583 N/A 3930.186 3923.339	190 1390 1042 234 N/A 265 278	5.9 2.6 5.4 5.1 N/A 4.8 3.9	No No Once No No No No	1.70 1.89 1.78 1.78 N/A 1.77	1.79 1.89 1.79 1.81 N/A 1.79	1.79  1.80  1.79  N/A  1.79  1.79	137 . 16
C15-1C-3A	36	NO	10/17/2001	121	JLAB - 02/06/02	μm/min Tot.= 25 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm	15 min	2/17/2001 2/17/2001 9/3/2002 20up/20dwn	JLAB - 600 C - 10 hrs A0 - 150C Wrap Bake 10/30/2002 - 11/3/2002  JLAB - 600 C - 10 hrs	11/16/2001 6/27/2002 11/7/2002 2/23/2002 3/15/2002 5/1/2002	3950.930 3930.016 3976.415 3930.583 N/A 3930.186	190 1390 1042 234 N/A 265	5.9 2.6 5.4 5.1 N/A 4.8	No No No No No No No No N/A No	1.78 1.78 1.78 N/A 1.78	1.70 1.89 1.79 1.81 N/A 1.79	1.79 1.80 1.79 N/A 1.78	137 . 16
C15-1C-3A	36	NO NO	10/17/2001	121	JLAB - 02/06/02 JLAB - 02/06/02 JLAB - 05/30/02	μm/min Tot.= 25 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm	15 min	2/17/2001 2/3/2002	JLAB - 600 C - 10 hrs A0 - 150C Wrap Bake 10/30/2002 - 11/3/2002	11/16/2001 6/27/2002 11/7/2002 11/7/2002 3/15/2002 5/1/2002 10/2/2002 12/4/2002	3950.930 3930.016 3976.415 3930.583 N/A 3930.186 3923.339 3923.307 3923.838	190 1390 1042 234 N/A 265 278 298	5.9 2.6 5.4 5.1 N/A 4.8 3.9 3.4 3.6	No	1.78  1.78  1.78  1.78  N/A  1.78  1.77  1.79  1.78	1.70  1.89  1.79  1.81  N/A  1.79  1.79  1.79	1.79  1.80  1.79  N/A  1.78  1.79  1.79	
	36	NO NO Probe Fla	10/17/2001	121 109	JLAB - 02/06/02  JLAB - 02/06/02  JLAB - 05/30/02	μm/min Tot.= 25 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm  4 x 1 minute BCP @ 5.4 μm/min Tot.=22 μm	15 min	2/17/2001 2/17/2001 9/3/2002 20up/20dwn 11/19/2002	JLAB - 600 C - 10 hrs A0 - 150C Wrap Bake 10/30/2002 - 11/3/2002  JLAB - 600 C - 10 hrs	11/16/2001 6/27/2002 11/7/2002 11/7/2002 2/23/2002 3/15/2002 5/1/2002 10/2/2002	3950.930 3930.016 3976.415 3930.583 N/A 3930.186 3923.339 3923.307	190 1390 1042 234 N/A 265 278 298	5.9 2.6 5.4 5.1 N/A 4.8 3.9 3.4	No No No No No No No No No	1.70  1.89  1.78  1.78  N/A  1.78  1.77  1.79	1.70  1.89  1.79  1.81  N/A  1.79  1.79	1.79  1.80  1.79  N/A  1.78  1.79  1.79	137 16 18 20

Cavity Notation: XXX-nC-sm

XXX = profile shape n = number of cells \* See Rs Correction Note Based upon End Effects Extraction One Page 3 of this Cavity History Table

s = serial number (chronological order of fabrication)

m = Niobium shipment utilized for fabrication

## **Temperature Measurements on C15-3C-5** (preliminary note)

Measurements of cavity temperature were performed on C15-3C-5 on 7/17/02. Results were obtained for the following conditions:

- Continuous power (cw) operation
- Pulsed power operation (700 ms period, 250 ms width)
- Quench mode operation (breakdown frequency measured from RF system ~ 9.3 Hz)

Two temperature sensor holders with four CERNOX sensors each like the one shown in the following figure were used:



The CERNOX sensors were spring loaded against the cavity iris external wall. Sensors A (E) and C (G) were aligned with the flat portion of the cavity, and sensors B (F) and D (H) were aligned with the circular portion.

The first holder with sensors A, B, C, and D was located between the first and second cell, and the second holder with sensors E, F, G, and H was located between the second and the third cell.

Following is a series of plots showing measurement results for different condition. Note that sensor "C" registered a much higher temperature when power was on, and it responded clearly to quench events. The detail of the quench pulse shows a behavior consistent with crossing the Lambda point at 2.17 K. Another interesting observation is that other sensors show a cooling effect when power was applied, and this result is being analyzed by Moyses to determine if there is a superfluid heat transfer mechanism taking place bringing colder helium to the "hot spot" around the location of sensor C.

This is a preliminary note, and a more detailed presentation of results and analysis will follow.

Onset of Quench Mode (Breakdown Frequency from RF system ~ 9.3 Hz)



